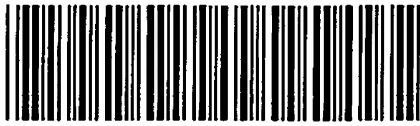


**Search Notes**

Application/Control No.

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Examiner

TAN X. DINH

Applicant(s)/Patent under  
Reexamination

AIKOH ET AL.

Art Unit

2653

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (see search history printout)	9/8/2005	T.D